

The invention relates to the field of computer engineering and microelectronics and may be applied for the production and exploitation of superintegrated circuits with built-in testing and diagnostics means.

The device contains a counter 1, a group of counters 2, on-line storage 3, a modulo two summer 4, a register 5, a trigger flip-flop 6, three OR gates 7, 8 and 9, two multiplexers 10 and 11, an indication output 13.

The result of the invention consists in the identification and localization of the defective storage register.

Claims: 1

Fig.: 3

